Notice of References Cited Application/Control No. 10/604,671 Examiner Christopher Verdier Applicant(s)/Patent Under Reexamination LIU ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,145,912 A	08-1964	WEIS	415/204
*	В	US-4,063,060 A	12-1977	Litch, III	219/93
*	С	US-4,647,271 A	03-1987	Nagai et al.	416/186R
*	D	US-3,775,029 A	11-1973	Ranz	415/206
*	E	US-5,088,886 A	02-1992	Hopkins	415/206
*	F	US-3,811,790 A	05-1974	Mikulina et al.	415/206
*	G	US-1,875,881 A	09-1932	CLARK	415/206
*	Н	US-6,210,109 B1	04-2001	Will et al.	415/204
	i	US-			
-	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-59-93,997-A	05-1984	Japan		415/206
	0	JP-55-134,797-A	10-1980	Japan		416/185
	Р	GB-941,343-A	11-1963	United Kingdom		416/186R
	Q	DE-4,023,724-A1	04-1991	Germany		415/208.1
	R	SU-1,262,122-A1	10-1986	Soviet Union		415/206
	s	-				
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	>	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.